

SPECIFICATIONS

$AV_{DD} = DV_{DD} = V_{VCO} = SDV_{DD} = V_P = 3.3 \text{ V} \pm 10\%$; $AGND = DGND = 0 \text{ V}$; $T_A = T_{MIN}$ to T_{MAX} , unless otherwise noted. Operating temperature range is -40°C to $+85^\circ\text{C}$.

Table 1.

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
REF _{IN} CHARACTERISTICS					
Input Frequency	10		250	MHz	For f < 10 MHz, ensure slew rate > 21 V/μs Biased at AV _{DD} /2; ac coupling ensures AV _{DD} /2 bias
Input Sensitivity	0.7		AV _{DD}	V p-p	
Input Capacitance		10		pF	
Input Current			±60	μA	
PHASE FREQUENCY DETECTOR (PFD)					
Phase Detector Frequency			32	MHz	Fractional-N Integer-N (band select enabled) Integer-N (band select disabled)
			45	MHz	
			90	MHz	
CHARGE PUMP					
I _{CP} Sink/Source ¹					R _{SET} = 5.1 kΩ
High Value		5		mA	
Low Value		0.312		mA	
R _{SET} Range	3.9		10	kΩ	
Sink and Source Current Matching		2		%	0.5 V ≤ V _{CP} ≤ 2.5 V
I _{CP} vs. V _{CP}		1.5		%	0.5 V ≤ V _{CP} ≤ 2.5 V
I _{CP} vs. Temperature		2		%	V _{CP} = 2.0 V
LOGIC INPUTS					
Input High Voltage, V _{INH}	1.5			V	
Input Low Voltage, V _{INL}			0.6	V	
Input Current, I _{INH} /I _{INL}			±1	μA	
Input Capacitance, C _{IN}		3.0		pF	
LOGIC OUTPUTS					
Output High Voltage, V _{OH}	DV _{DD} – 0.4			V	CMOS output selected
Output High Current, I _{OH}			500	μA	
Output Low Voltage, V _{OL}			0.4	V	I _{OL} = 500 μA
POWER SUPPLIES					
AV _{DD}	3.0		3.6	V	These voltages must equal AV _{DD}
DV _{DD} , V _{VCO} , SDV _{DD} , V _P		AV _{DD}			
DI _{DD} + AI _{DD} ²		21	27	mA	Each output divide-by-2 consumes 6 mA
Output Dividers		6 to 36		mA	
I _{VCO} ²		70	80	mA	RF output stage is programmable
I _{RFOUT} ²		21	26	mA	
Low Power Sleep Mode		7	10	μA	
RF OUTPUT CHARACTERISTICS					
VCO Output Frequency	2200		4400	MHz	Fundamental VCO mode 2200 MHz fundamental output and divide-by-64 selected
Minimum VCO Output Frequency Using Dividers	34.375			MHz	
VCO Sensitivity, K _V		40		MHz/V	Into 2.00 VSWR load Fundamental VCO output Divided VCO output Fundamental VCO output Divided VCO output
Frequency Pushing (Open-Loop)		1		MHz/V	
Frequency Pulling (Open-Loop)		90		kHz	
Harmonic Content (Second)		–19		dBc	
		–20		dBc	
Harmonic Content (Third)		–13		dBc	
		–10		dBc	

Parameter	Min	Typ	Max	Unit	Test Conditions/Comments
Minimum RF Output Power ³		−4		dBm	Programmable in 3 dB steps
Maximum RF Output Power ³		5		dBm	
Output Power Variation		±1		dB	
Minimum VCO Tuning Voltage		0.5		V	
Maximum VCO Tuning Voltage		2.5		V	
NOISE CHARACTERISTICS					
VCO Phase Noise Performance					VCO noise is measured in open-loop conditions
		−89		dBc/Hz	10 kHz offset from 2.2 GHz carrier
		−114		dBc/Hz	100 kHz offset from 2.2 GHz carrier
		−134		dBc/Hz	1 MHz offset from 2.2 GHz carrier
		−148		dBc/Hz	5 MHz offset from 2.2 GHz carrier
		−86		dBc/Hz	10 kHz offset from 3.3 GHz carrier
		−111		dBc/Hz	100 kHz offset from 3.3 GHz carrier
		−134		dBc/Hz	1 MHz offset from 3.3 GHz carrier
		−145		dBc/Hz	5 MHz offset from 3.3 GHz carrier
		−83		dBc/Hz	10 kHz offset from 4.4 GHz carrier
		−110		dBc/Hz	100 kHz offset from 4.4 GHz carrier
		−131		dBc/Hz	1 MHz offset from 4.4 GHz carrier
		−145		dBc/Hz	5 MHz offset from 4.4 GHz carrier
Normalized Phase Noise Floor (PN _{SYNTH}) ⁴					PLL loop BW = 500 kHz
		−220		dBc/Hz	ABP = 6 ns
		−221		dBc/Hz	ABP = 3 ns
Normalized 1/f Noise (PN _{1_f}) ⁵					10 kHz offset; normalized to 1 GHz
		−116		dBc/Hz	ABP = 6 ns
		−118		dBc/Hz	ABP = 3 ns
In-Band Phase Noise		−100		dBc/Hz	3 kHz from 2111.28 MHz carrier
Integrated RMS Jitter ⁶		0.27		ps	
Spurious Signals Due to PFD Frequency		−80		dBc	
Level of Signal with RF Mute Enabled		−40		dBm	

¹ I_{CP} is internally modified to maintain constant loop gain over the frequency range.

² $T_A = 25^\circ\text{C}$; $AV_{DD} = DV_{DD} = V_{VCO} = 3.3\text{ V}$; prescaler = 8/9; $f_{REFIN} = 100\text{ MHz}$; $f_{PFD} = 25\text{ MHz}$; $f_{RF} = 4.4\text{ GHz}$.

³ Using 50 Ω resistors to V_{VCO} , into a 50 Ω load. Power measured with auxiliary RF output disabled. The current consumption of the auxiliary output is the same as for the main output.

⁴ The synthesizer phase noise floor is estimated by measuring the in-band phase noise at the output of the VCO and subtracting $20 \log N$ (where N is the N divider value) and $10 \log f_{PFD}$. To calculate in-band phase noise performance as seen at the VCO output, use the following formula: $PN_{SYNTH} = PN_{TOT} - 10 \log(f_{PFD}) - 20 \log N$.

⁵ The PLL phase noise is composed of flicker (1/f) noise plus the normalized PLL noise floor. The formula for calculating the 1/f noise contribution at an RF frequency (f_{RF}) and at a frequency offset (f) is given by $PN = PN_{1-f} + 10 \log(10 \text{ kHz}/f) + 20 \log(f_{RF}/1 \text{ GHz})$. Both the normalized phase noise floor and flicker noise are modeled in [ADIsimPLL](#).

⁶ $f_{REFIN} = 122.88\text{ MHz}$; $f_{PFD} = 30.72\text{ MHz}$; VCO frequency = 4222.56 MHz; $f_{RF} = 2111.28\text{ MHz}$; N = 137; loop BW = 60 kHz; $I_{CP} = 2.5\text{ mA}$; low noise mode. The noise was measured with an EVAL-ADF4351EB1Z and the Rohde & Schwarz FSUP signal source analyzer.

TIMING CHARACTERISTICS

$AV_{DD} = DV_{DD} = V_{VCO} = SDV_{DD} = V_P = 3.3\text{ V} \pm 10\%$; $AGND = DGND = 0\text{ V}$; 1.8 V and 3 V logic levels used; $T_A = T_{MIN}$ to T_{MAX} , unless otherwise noted.

Table 2.

Parameter	Limit	Unit	Description
t_1	20	ns min	LE setup time
t_2	10	ns min	DATA to CLK setup time
t_3	10	ns min	DATA to CLK hold time
t_4	25	ns min	CLK high duration
t_5	25	ns min	CLK low duration
t_6	10	ns min	CLK to LE setup time
t_7	20	ns min	LE pulse width

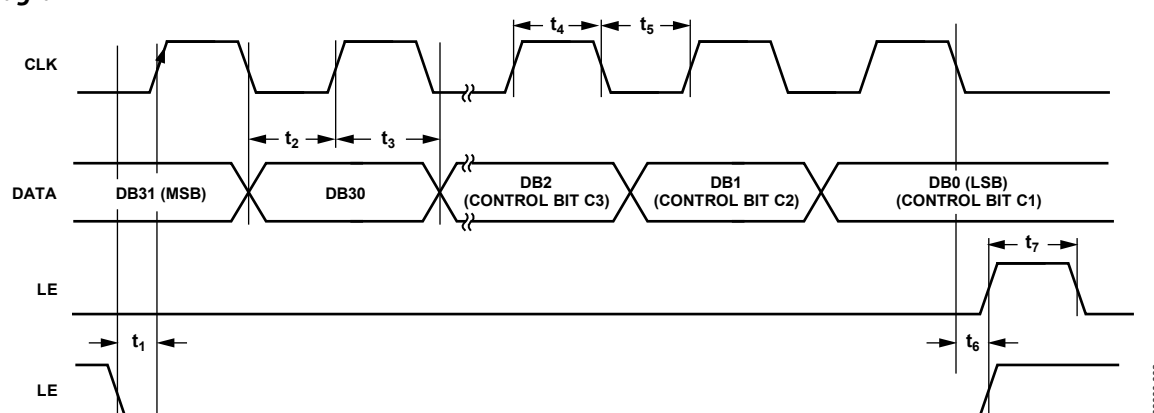
Timing Diagram

Figure 2. Timing Diagram

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